DATASHEET

UF3C120080B7S

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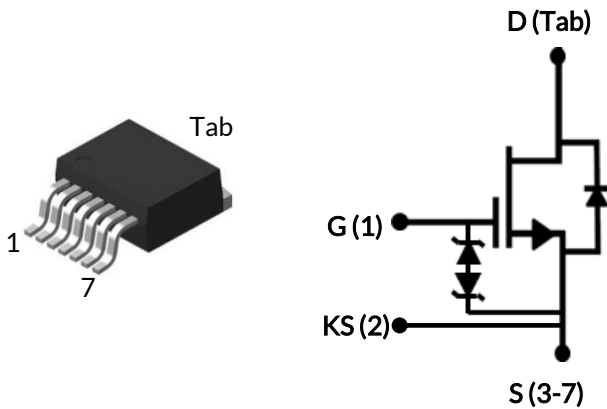| Part Number	Package	Marking
UF3C120080B7S	D²PAK-7L	UF3C120080B7S

1200V-85mΩ SiC FET

Rev. A, November 2020

Description

This SiC FET device is based on a unique 'cascode' circuit configuration, in which a normally-on SiC JFET is co-packaged with a Si MOSFET to produce a normally-off SiC FET device. The device's standard gate-drive characteristics allows for a true "drop-in replacement" to Si IGBTs, Si FETs, SiC MOSFETs or Si superjunction devices. Available in the D²PAK-7L package, this device exhibits ultra-low gate charge and exceptional reverse recovery characteristics, making it ideal for switching inductive loads , and any application requiring standard gate drive.

Features

- On-resistance $R_{DS(on)}$: 85mΩ (typ)
- Operating temperature: 175°C (max)
- Excellent reverse recovery: Q_{rr} = 140nC
- Low body diode V_{FSD}: 1.5V
- Low gate charge: Q_G = 23nC
- Threshold voltage $V_{G(th)}$: 4.8V (typ) allowing 0 to 15V drive
- Package creepage and clearance distance > 6.1mm
- Kelvin source pin for optimized switching performance
- ESD protected, HBM class 2

Typical applications

Any controlled environment such as

- Telecom and Server Power
- Industrial power supplies
- Power factor correction modules
- Motor drives
- Induction heating

Maximum Ratings

Parameter	Symbol	Test Conditions	Value	Units
Drain-source voltage	V_{DS}		1200	V
Gate-source voltage	V_{GS}	DC	-25 to +25	V
Continuous drain current [1]	I_D	$T_C = 25°C$	28.8	A
		$T_C = 100°C$	21	A
Pulsed drain current [2]	I_{DM}	$T_C = 25°C$	77	A
Single pulsed avalanche energy [3]	E_{AS}	L=15mH, I_{AS} =2.8A	58.5	mJ
Power dissipation	P_{tot}	$T_C = 25°C$	190	W
Maximum junction temperature	$T_{J,max}$		175	°C
Operating and storage temperature	T_J, T_{STG}		-55 to 175	°C
Reflow soldering temperature	T_{solder}	reflow MSL 3	260	°C

1. Limited by $T_{J,max}$
2. Pulse width t_p limited by $T_{J,max}$
3. Starting $T_J = 25°C$

Thermal Characteristics

Parameter	Symbol	Test Conditions	Value			Units
			Min	Typ	Max	
Thermal resistance, junction-to-case	$R_{\theta JC}$			0.61	0.79	°C/W

Electrical Characteristics (T_J = +25°C unless otherwise specified)

Typical Performance - Static

Parameter	Symbol	Test Conditions	Value			Units
			Min	Typ	Max	
Drain-source breakdown voltage	BV_{DS}	V_{GS}=0V, I_D=1mA	1200			V
Total drain leakage current	I_{DSS}	V_{DS}=1200V, V_{GS}=0V, T_J=25°C		0.7	75	μA
		V_{DS}=1200V, V_{GS}=0V, T_J=175°C		3		
Total gate leakage current	I_{GSS}	V_{DS}=0V, T_J=25°C, V_{GS}=-20V / +20V		6	± 20	μA
Drain-source on-resistance	$R_{DS(on)}$	V_{GS}=12V, I_D=20A, T_J=25°C		85	105	mΩ
		V_{GS}=12V, I_D=20A, T_J=125°C		135		
		V_{GS}=12V, I_D=20A, T_J=175°C		177		
Gate threshold voltage	$V_{G(th)}$	V_{DS}=5V, I_D=10mA	4	4.8	6	V
Gate resistance	R_G	f=1MHz, open drain		4.2		Ω

Typical Performance - Reverse Diode

Parameter	Symbol	Test Conditions	Value			Units
			Min	Typ	Max	
Diode continuous forward current [1]	I_S	T_C=25°C			28.8	A
Diode pulse current [2]	$I_{S,pulse}$	T_C=25°C			77	A
Forward voltage	V_{FSD}	V_{GS}=0V, I_F=10A, T_J=25°C		1.5	2	V
		V_{GS}=0V, I_F=10A, T_J=175°C		2		
Reverse recovery charge	Q_{rr}	V_R=800V, I_F=20A, V_{GS}=-5V, R_{G_EXT}=22Ω di/dt=2800A/μs, T_J=25°C		140		nC
Reverse recovery time	t_{rr}			23		ns
Reverse recovery charge	Q_{rr}	V_R=800V, I_F=20A, V_{GS}=-5V, R_{G_EXT}=22Ω di/dt=2800A/μs, T_J=150°C		118		nC
Reverse recovery time	t_{rr}			19		ns

Typical Performance - Dynamic

Parameter	Symbol	Test Conditions	Value			Units
			Min	Typ	Max	
Input capacitance	C_{iss}	V_{DS}=100V, V_{GS}=0V f=100kHz		754		pF
Output capacitance	C_{oss}			97		
Reverse transfer capacitance	C_{rss}			0.8		
Effective output capacitance, energy related	$C_{oss(er)}$	V_{DS}=0V to 800V, V_{GS}=0V		54		pF
Effective output capacitance, time related	$C_{oss(tr)}$	V_{DS}=0V to 800V, V_{GS}=0V		122		pF
C_{OSS} stored energy	E_{oss}	V_{DS}=800V, V_{GS}=0V		17.3		μJ
Total gate charge	Q_G	V_{DS}=800V, I_D=20A, V_{GS} = -5V to 12V		23		nC
Gate-drain charge	Q_{GD}			5		
Gate-source charge	Q_{GS}			11		
Turn-on delay time	$t_{d(on)}$	V_{DS}=800V, I_D=20A, Gate Driver =-5V to +12V, Turn-on $R_{G,EXT}$=8.5Ω, Turn-off $R_{G,EXT}$=22Ω Inductive Load, FWD: same device with V_{GS} = -5V, R_G = 22Ω, T_J=25°C		33		ns
Rise time	t_r			7		
Turn-off delay time	$t_{d(off)}$			30		
Fall time	t_f			9		
Turn-on energy	E_{ON}			340		μJ
Turn-off energy	E_{OFF}			48		
Total switching energy	E_{TOTAL}			388		
Turn-on delay time	$t_{d(on)}$	V_{DS}=800V, I_D=20A, Gate Driver =-5V to +12V, Turn-on $R_{G,EXT}$=8.5Ω, Turn-off $R_{G,EXT}$=22Ω Inductive Load, FWD: same device with V_{GS} = -5V, R_G = 22Ω, T_J=150°C		31		ns
Rise time	t_r			6		
Turn-off delay time	$t_{d(off)}$			30		
Fall time	t_f			8		
Turn-on energy	E_{ON}			312		μJ
Turn-off energy	E_{OFF}			42		
Total switching energy	E_{TOTAL}			354		

Typical Performance Diagrams
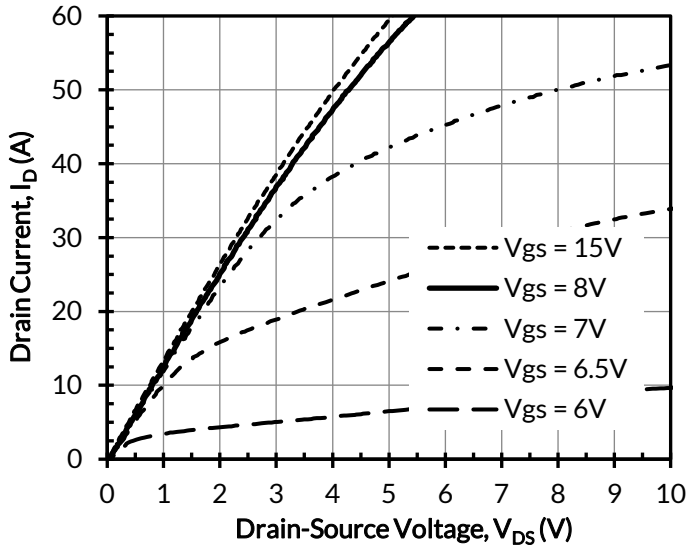
Figure 1. Typical output characteristics at T_J = - 55°C, tp < 250µs
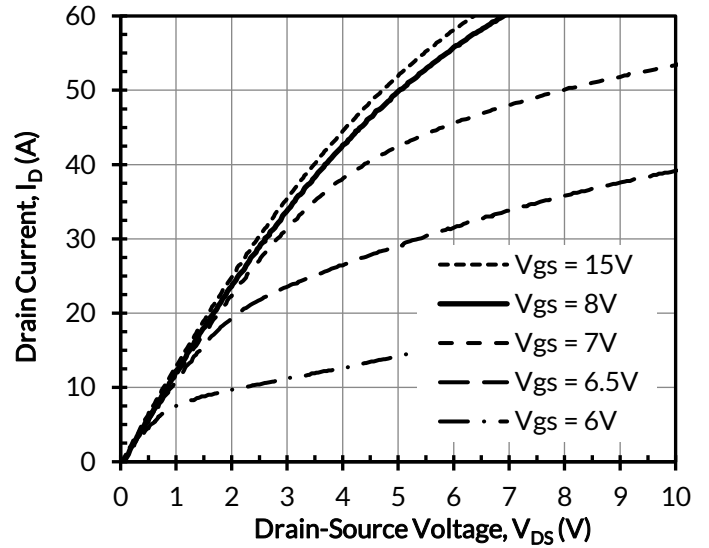
Figure 2. Typical output characteristics at T_J = 25°C, tp < 250µs

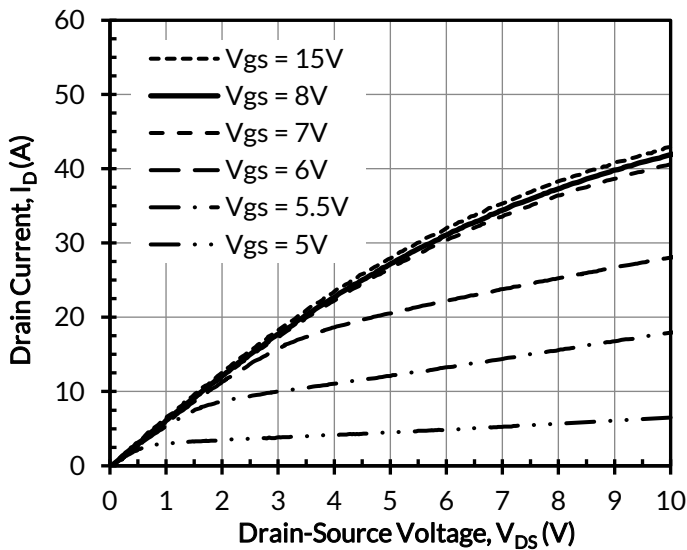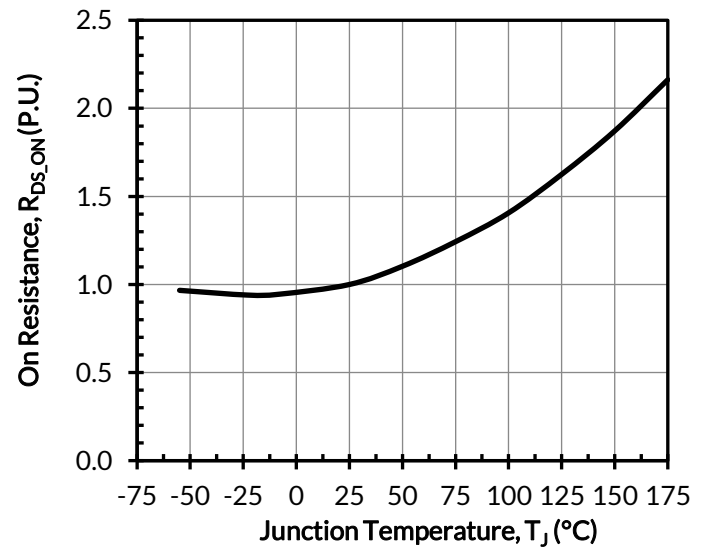Figure 3. Typical output characteristics at T_J = 175°C, tp < 250µs

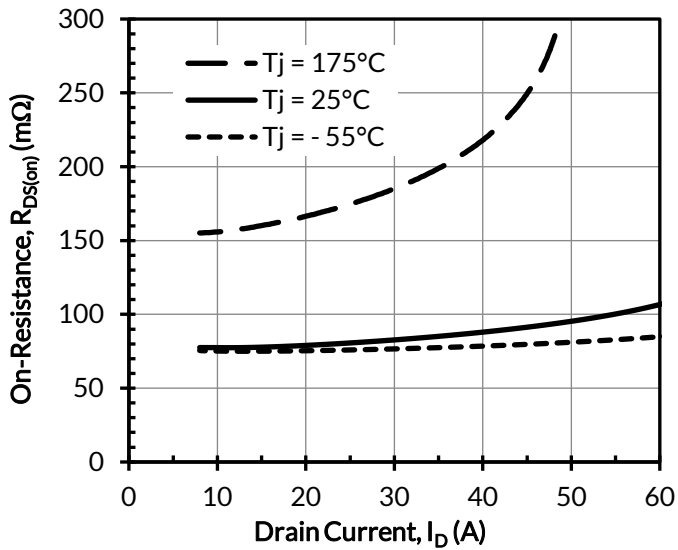Figure 4. Normalized on-resistance vs. temperature at V_{GS} = 12V and I_D = 20A

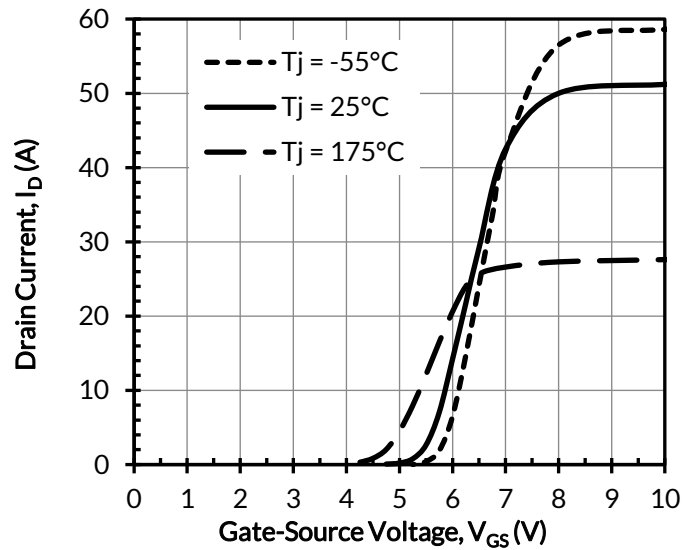Figure 5. Typical drain-source on-resistances at V_{GS} = 12V

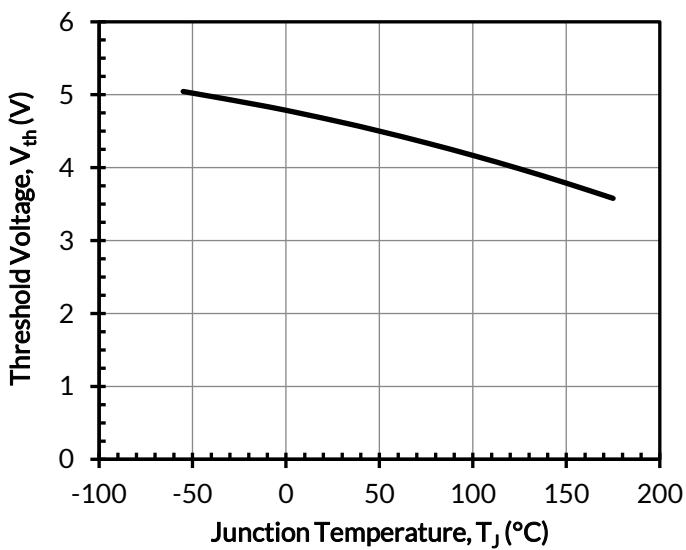Figure 6. Typical transfer characteristics at V_{DS} = 5V

Figure 7. Threshold voltage vs. junction temperature at V_{DS} = 5V and I_D = 10mA
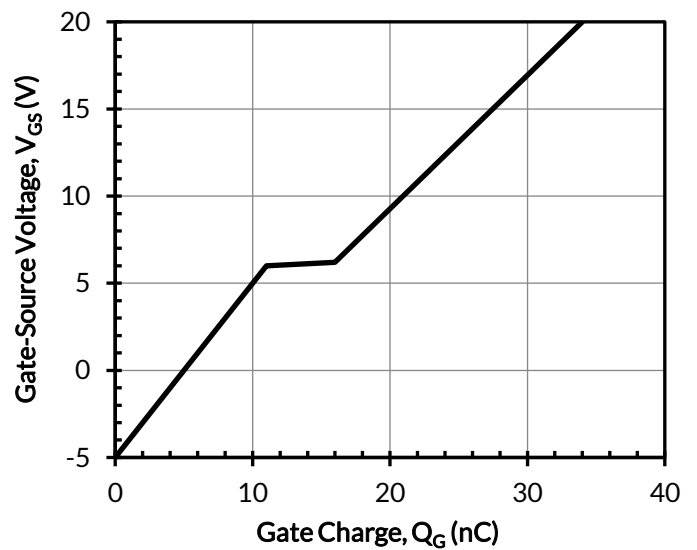
Figure 8. Typical gate charge at V_{DS} = 800V and I_D = 20A

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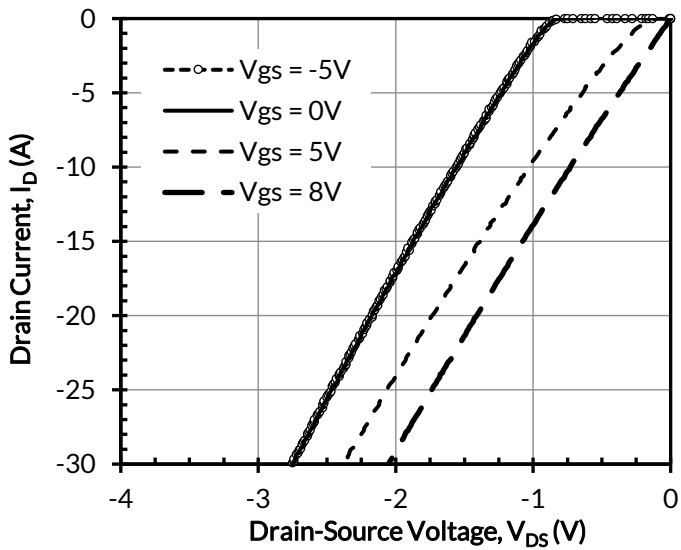
Figure 9. 3rd quadrant characteristics at T_J = -55°C
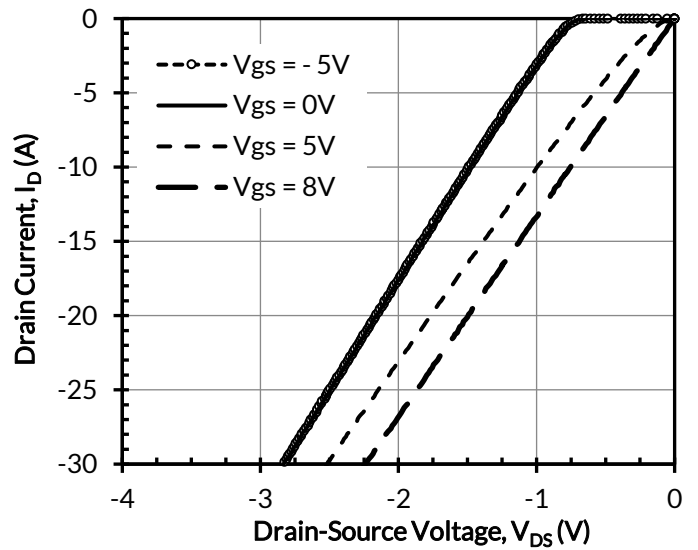
Figure 10. 3rd quadrant characteristics at T_J = 25°C
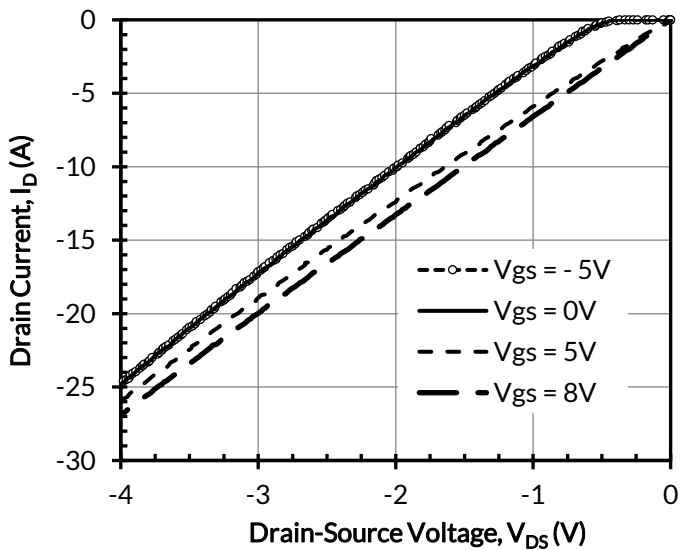
Figure 11. 3rd quadrant characteristics at T_J = 175°C
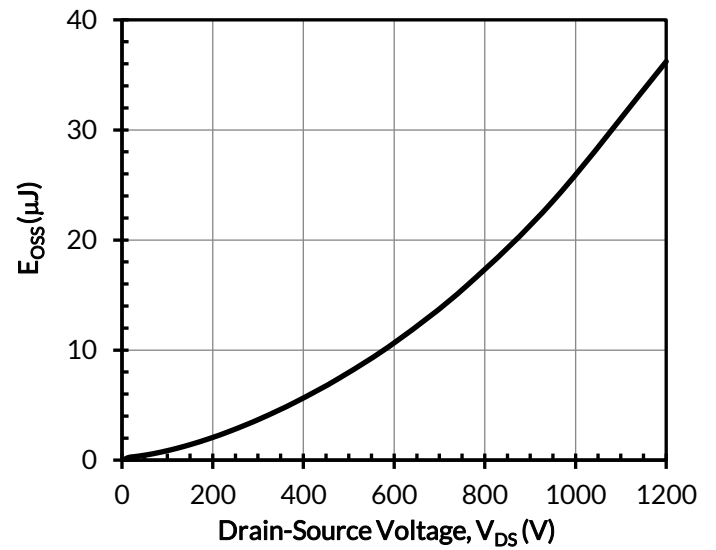
Figure 12. Typical stored energy in C_{OSS} at V_{GS} = 0V
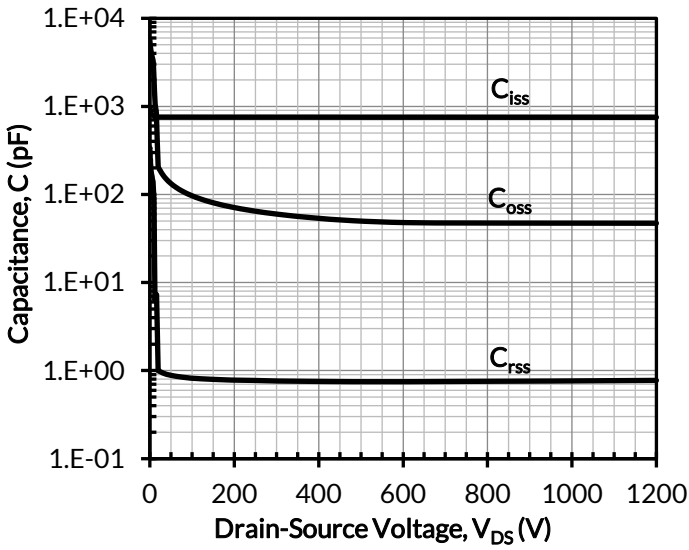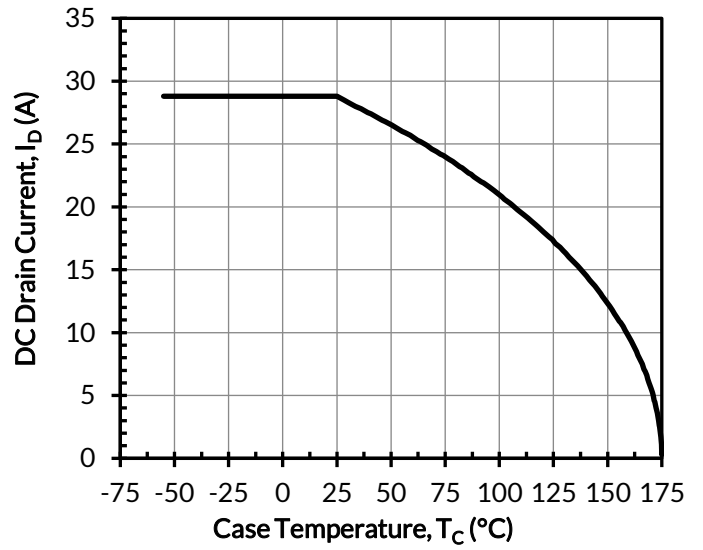
Figure 13. Typical capacitances at f = 100kHz and V_{GS} = 0V
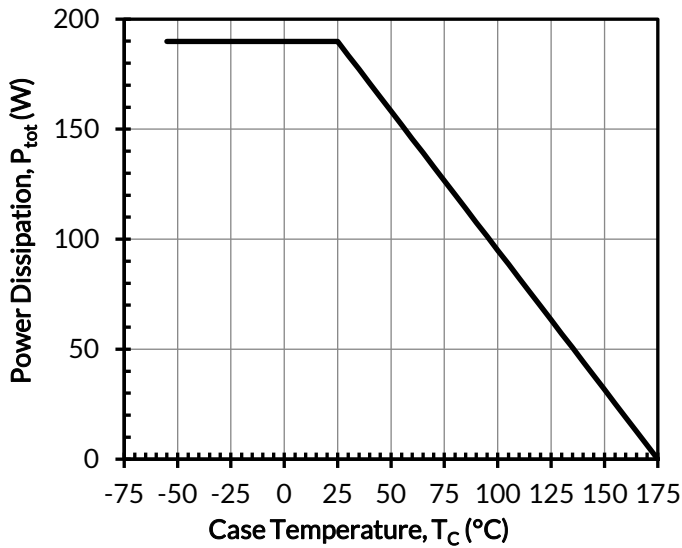

Figure 14. DC drain current derating

Figure 15. Total power dissipation

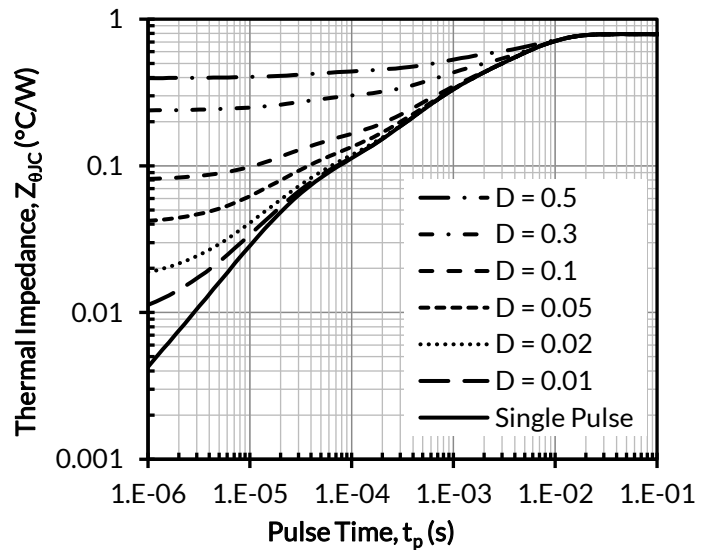Figure 16. Maximum transient thermal impedance
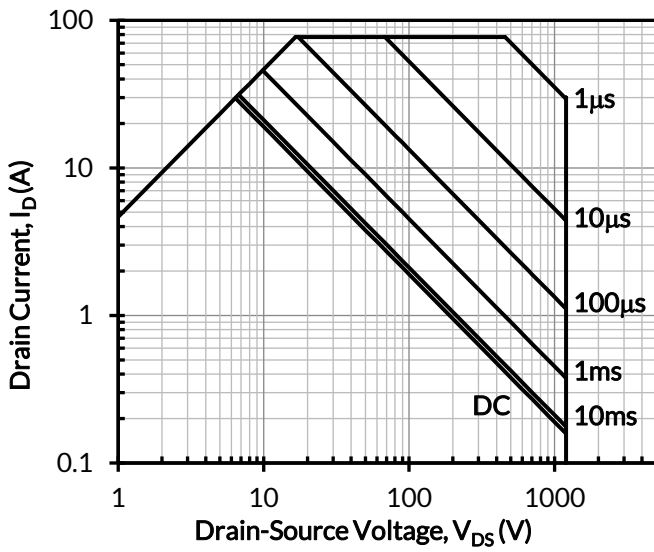
Figure 17. Safe operation area at T_C = 25°C, D = 0, Parameter t_p
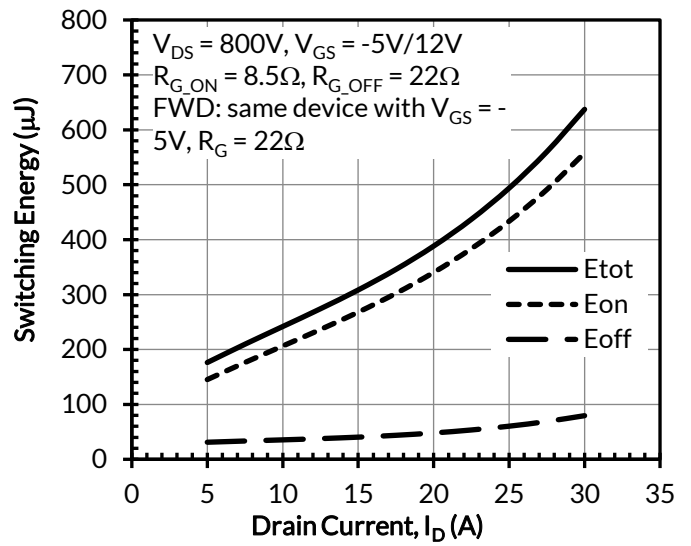

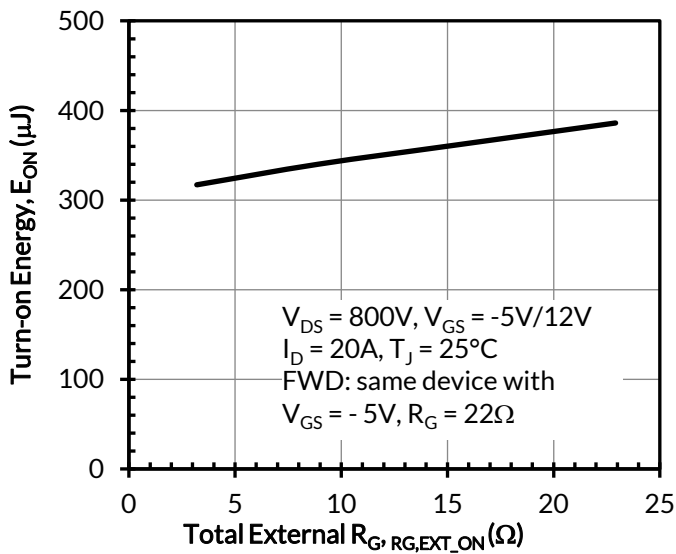Figure 18. Clamped inductive switching energy vs. drain current at T_J = 25°C

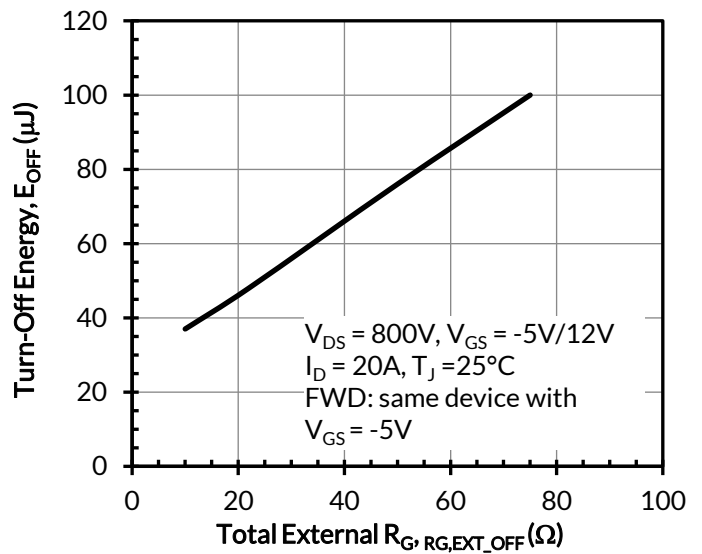Figure 19. Clamped inductive switching turn-on energy vs. R_{G,EXT_ON}

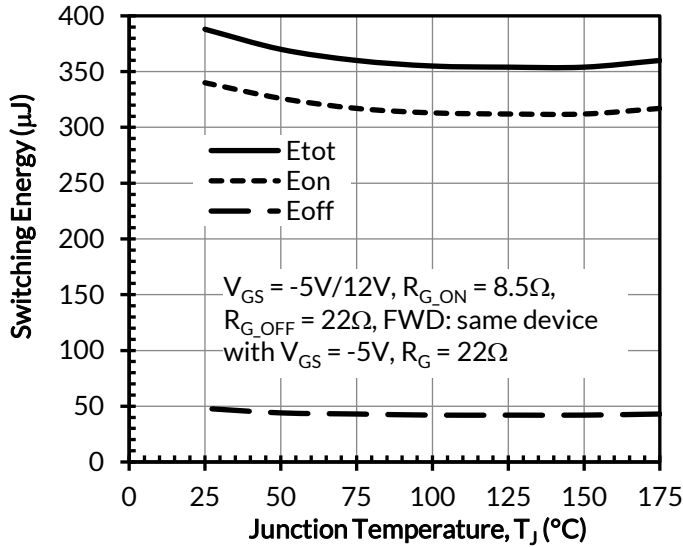Figure 20. Clamped inductive switching turn-off energy vs. R_{G,EXT_OFF}

Figure 21. Clamped inductive switching energy vs. junction temperature at V_{DS} = 800V and I_D = 20A
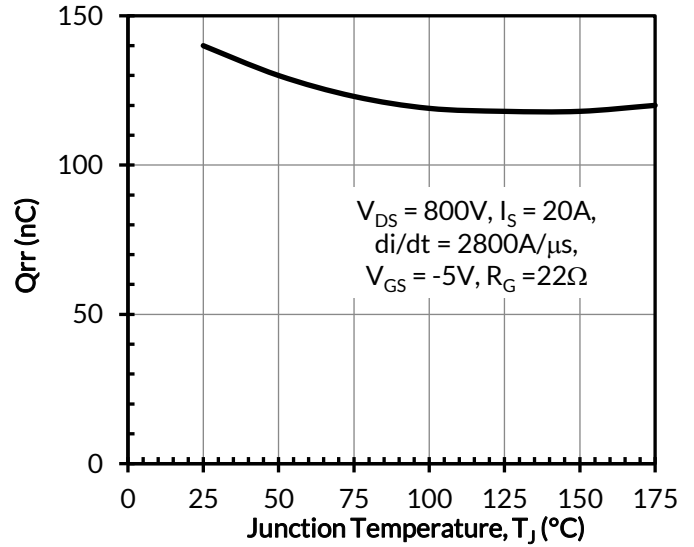

Figure 22. Reverse recovery charge Qrr vs. junction temperature

Applications Information

SiC FETs are enhancement-mode power switches formed by a high-voltage SiC depletion-mode JFET and a low-voltage silicon MOSFET connected in series. The silicon MOSFET serves as the control unit while the SiC JFET provides high voltage blocking in the off state. This combination of devices in a single package provides compatibility with standard gate drivers and offers superior performance in terms of low on-resistance ($R_{DS(on)}$), output capacitance (C_{oss}), gate charge (Q_G), and reverse recovery charge (Qrr) leading to low conduction and switching losses. The SiC FETs also provide excellent reverse conduction capability eliminating the need for an external anti-parallel diode.

Like other high performance power switches, proper PCB layout design to minimize circuit parasitics is strongly recommended due to the high dv/dt and di/dt rates. An external gate resistor is recommended when the FET is working in the diode mode in order to achieve the optimum reverse recovery performance. For more information on SiC FET operation, see www.unitedsic.com.

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